

47 CFR PART 15 SUBPART B

TEST REPORT

of

GSM DeskPhone

Model Name:

WD210P

Brand Name:

Avvio

Report No.:

SZ08100090E01

FCC ID:

WVB-WD210P

prepared for

Brightstar Corporation.

9725 NW 117th Ave#300-Miami-FL-33178 USA

Shenzhen Electronic Coduct Quality Testing Center

Morrab Laboratory
3/F, Electronic Texture Building Shahe Road, Xili,
Nanshan District, Shenzhen, 518055 P. R. China

1 #86 755 86130398











NOTE: This test report can be duplicated completely for the legal use with the approval of the applicant; it shall not be reproduced except in full, without the written approval of Shenzhen Electronic Product Quality Testing Center Morlab Laboratory. Any objections should be raised to us within thirty workdays since the date of issue.

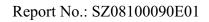




TABLE OF CONTENTS

1.	TEST CERTIFICATION
2.	GENERAL INFORMATION4
2.1	EUT Description4
2.2	Test Standards and Results5
2.3	Facilities and Accreditations6
2.3.1	Facilities6
2.3.2	Test Environment Conditions
2.3.3	Measurement Uncertainty6
3.	TEST CONDITIONS SETTING7
3.1	Test Mode
3.2	Test Setup and Equipments List8
3.2.1	Conducted Emission8
3.2.2	Radiated Emission9
4.	47 CFR PART 15B REQUIREMENTS10
4.1	Conducted Emission10
4.1.1	Requirement
4.1.2	Requirement
	Test Description
4.1.3	•
4.1.3 4.1.3.	Test Description
	Test Description
4.1.3.	Test Description
4.1.3. 4.1.3.	Test Description
4.1.3. 4.1.3. 4.2	Test Description 10 Test Result 10 1 GSM Test Mode 10 2 USB Test Mode 12 Radiated Emission 14





TEST CERTIFICATION 1.

Equipment under Test: GSM DeskPhone

Brand Name: Avvio Model Name: WD210P

FCC ID: WVB-WD210P

Applicant: Brightstar Corporation.

9725 NW 117th Ave#300-Miami-FL-33178 USA

Manufacturer: TechFaith Wireless Technology Group Limited.

No. 10A, Tower D2, IT Park, Electronic Town, Jiu Xian Qiao North Road,

Chao Yang District, Beijing, China (100015)

Emission Designator 300KGXW

Test Standards: 47 CFR Part 15 Subpart B

Test Date(s): November 13, 2008 -November 28, 2008

Test Result: PASS

* We Hereby Certify That:

The equipment under test was tested by Shenzhen Electronic Product Quality Testing Center Morlab Laboratory. The test data, data evaluation, test procedures and equipment configurations shown in this report were made in accordance with the requirement of related FCC rules.

The test results of this report only apply for the tested sample equipment identified above. The test report shall be invalid without all the signatures of the test engineer, the reviewer and the approver.

Tested by:

Li Yi

Reviewed by:

Wei Yanquan

Dated: 2008. (2.16

2008, 12.16

Approved by:



2. GENERAL INFORMATION

2.1 EUT Description

EUT Type GSM DeskPhone

Model Name..... WD210P

 Serial No.
 MD12092T000

 IMEI
 355000010004597

Hardware Version...... 8420038T200

Model Name: 49AA1200P3

Brand name: Avvio Capacitance: 1200mAh Rated voltage: 3.6V

Manufacturer: Shenzhen Grepow Battery Co., LTD

Manufacturer Address: Wushigang, Chuangyi Road , Longhua Village, Bao An

District, Shenzhen, P.R.China

Ancillary Equipment 1... AC Adapter (Charger for Battery)

Model Name: RD1201500-C55-1MG

Brand Name: Avvio

Serial No.: (n.a. marked #1 by test site)
Rated Input: ~ 100-240V, 0.6A,50/60Hz

Rated Output: = 12V, 1500mA

Manufacturer: Shenzhen Ruide Electronic Industrial Co. Ltd.

Manufacturer Address: 2nd floor, Block 2, MinQi Scientific Zone,

HongHuaLing, XiLi, Nanshan District, Shenzhen, China.

Wire Length: 140cm

- Note 1: The EUT is a GSM/GPRS Wireless telephone; it supports GSM 850MHz, 1900MHz. GSM 850MHz and 1900MHz are tested in this report.
- *Note 2:* The EUT is equipped with a T-Flash card slot; equipped with a special port which can be connected to the ancillary equipments supplied by the manufacturer
- *Note 3:* For a more detailed description, please refer to Specification or User's Manual supplied by the applicant and/or manufacturer.



2.2 Test Standards and Results

The objective of the report is to perform testing according to 47 CFR Part 15 Subpart B:

No.	Identity	Document Title
1	47 CFR Part 15	Radio Frequency Devices
	(10-1-05 Edition)	

Test detailed items/section required by FCC rules and results are as below:

No.	Section	Description	Result	Test date
1	15.107	Conducted Emission	PASS	2008-10-20
2	15.109	Radiated Emission	PASS	2008-10-24

NOTE:

The tests were performed according to the method of measurements prescribed in ANSI C63.4 2003.



2.3 Facilities and Accreditations

2.3.1 Facilities

Shenzhen Electronic Product Quality Testing Center Morlab Laboratory is a testing organization accredited by China National Accreditation Service for Conformity Assessment (CNAS) according to ISO/IEC 17025. The accreditation certificate number is L1659.

All measurement facilities used to collect the measurement data are located at Electronic Testing Building, Shahe Road, Xili, Nanshan District, Shenzhen 518055 CHINA. The test site is constructed in conformance with the requirements of ANSI C63.7, ANSI C63.4 and CISPR Publication 22; the FCC registration number is 741109.

2.3.2 Test Environment Conditions

During the measurement, the environmental conditions were within the listed ranges:

Temperature (°C):	20 - 25
Relative Humidity (%):	40 - 60
Atmospheric Pressure (kPa):	96

2.3.3 Measurement Uncertainty

The uncertainty is calculated using the methods suggested in the "Guide to the Expression of Uncertainty in Measurement" (GUM) published by ISO.

Uncertainty of Conducted Emission:	±1.8dB
Uncertainty of Radiated Emission:	±3.1dB



3. TEST CONDITIONS SETTING

3.1 Test Mode

1. GSM Test Mode

(1) The first test mode (GSM)

The EUT configuration of the emission tests is <u>EUT + Battery + Charger</u>.

During the measurement, the two GSM radios (GSM-1 and GSM-2) work together; but the GSM-1 works under Traffic operating mode and the GSM-2 works under Idle operating mode.

During the measurement of Traffic operating mode, a communication link was established between the EUT and a System Simulator (SS). The EUT operated at GSM 850MHz mid ARFCN (190) and maximum output power (level 5).

A communication link was established between the EUT and the Bluetooth earphone, and maintained until test end.

(2) The second test mode (GPRS)

The EUT configuration of the emission tests is EUT + Battery + Charger.

In this test mode, a GPRS link was established between the EUT and a System Simulator (SS); date was transmitted between EUT and System Simulator (SS), and maintained during the measurement.

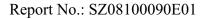
NOTE: All test modes are performed, only the worst cases are recorded in this report.

2. USB Test Mode

(1) The first test mode (USB)

The EUT configuration of the emission tests is <u>TransFlash Card + EUT + Battery + PC.</u>

In this test mode, the EUT with a TransFlash Card embedded is connected with a PC via a special USB cable supplied by applicant. During the measurement, a communication link was established between the EUT and a System Simulator (SS), simultaneity, the date is transmitting between the PC and the TransFlash Card of the EUT.

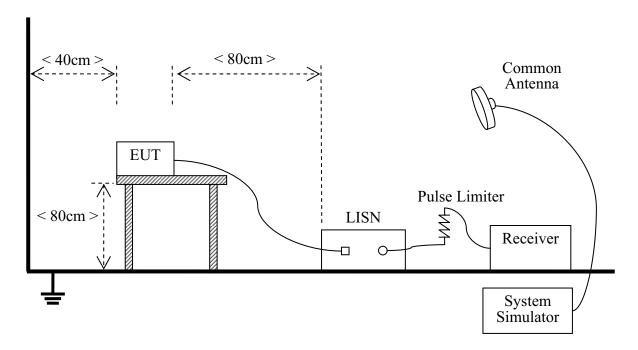




3.2 Test Setup and Equipments List

3.2.1 Conducted Emission

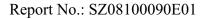
A. Test Setup:



The EUT is placed on a 0.8m high insulating table, which stands on the grounded conducting floor, and keeps 0.4m away from the grounded conducting wall. The EUT is connected to the power mains through a LISN which provides $50\Omega/50\mu H$ of coupling impedance for the measuring instrument. The Common Antenna is used for the call between the EUT and the System Simulator (SS). A Pulse Limiter is used to protect the measuring instrument. The factors of the whole test system are calibrated to correct the reading.

B. Equipments List:

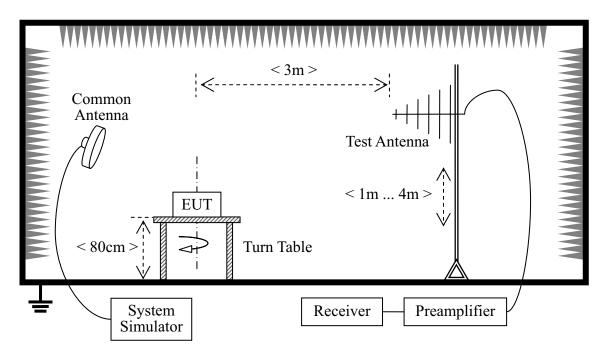
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due
Receiver	Agilent	E7405A	US44210471	2008.09	1 year
LISN	Schwarzbeck	NSLK 8127	812744	2008.09	1 year
Pulse Limiter (20dB)	Schwarzbeck	VTSD 9561-D	9391	(n.a.)	(n.a.)
System Simulator	Agilent	E5515C	GB43130131	2008.09	1 year
Personal Computer	IBM	IBM_T20	(n.a)	(n.a.)	(n.a.)
T-Flash Card	SanDisk	256MB	(n.a.)	(n.a.)	(n.a.)





3.2.2 Radiated Emission

C. Test Setup:



The test is performed in a 3m Semi-Anechoic Chamber; the antenna factor, cable loss and so on of the site (factors) is calculated to correct the reading. The EUT is placed on a 0.8m high insulating Turn Table, and keeps 3m away from the Test Antenna, which is mounted on a variable-height antenna master tower. The Common Antenna is used for the call between the EUT and the System Simulator (SS).

D. Equipments List:

Description	Manufacturer	Model	Serial No.	Cal.	Cal. Due
				Date	
Receiver	Agilent	E7405A	US44210471	2008.09	1 year
Semi-Anechoic	Albatross	9m*6m*6m	(n.a.)	2008.08	2year
Chamber					
Test Antenna - Bi-Log	Schwarzbeck	VULB 9163	9163-274	2008.08	1 year
Test Antenna - Horn	Schwarzbeck	BBHA 9120C	9120C-384	2008.08	1 year
System Simulator	Agilent	E5515C	GB43130131	2008.09	1 year
Personal Computer	IBM	IBM_T20	(n.a)	(n.a.)	(n.a.)
Bluetooth-Headset	Nokia	HS-36W	(n.a.)	(n.a.)	(n.a.)
T-Flash Card	SanDisk	256MB	(n.a.)	(n.a.)	(n.a.)



4. 47 CFR PART 15B REQUIREMENTS

4.1 Conducted Emission

4.1.1 Requirement

According to FCC section 15.107, the radio frequency voltage that is conducted back onto the AC power line on any frequency within the band 150kHz to 30MHz shall not exceed the limits in the following table, as measured using a $50\mu\text{H}/50\Omega$ line impedance stabilization network (LISN).

Engagement non as (MIIIa)	Conducted Limit (dBµV)			
Frequency range (MHz)	Quai-peak	Average		
0.15 - 0.50	66 to 56	56 to 46		
0.50 - 5	56	46		
5 - 30	60	50		

NOTE:

- a) The limit subjects to the Class B digital device.
- b) The lower limit shall apply at the band edges.
- c) The limit decreases linearly with the logarithm of the frequency in the range 0.15 0.50MHz.

4.1.2 Test Description

See section 3.2.1 of this report.

4.1.3 Test Result

The maximum conducted interference is searched using Peak (PK), Quasi-peak (QP) and Average (AV) detectors; the emission levels more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed. All test modes are considered, refer to recorded points and plots below.

4.1.3.1 GSM Test Mode

A. Test Verdict Recorded for Suspicious Points:

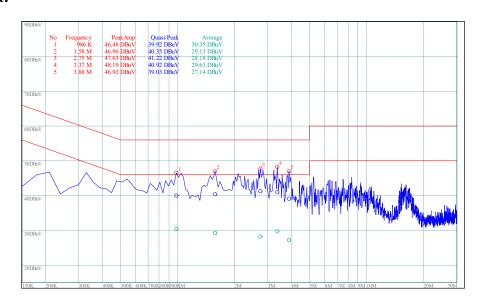
No.	@Frequency	Meası	ured Emissio	Limit (Verdict			
INO.	(MHz)	PK	QP	AV	Phase	QP	AV	verdict
1	0.986	46.48	39.92	30.35	L	56.0	46.0	PASS
2	1.58	46.96	40.35	29.13	L	56.0	46.0	PASS



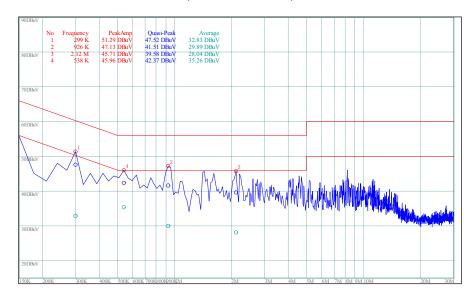


Nia	@Frequency	Measi	ured Emission	Limit (Vandiat			
No.	(MHz)	PK	QP	AV	Phase	QP	AV	Verdict
3	2.75	47.63	41.22	28.18	L	56.0	46.0	PASS
4	3.37	48.19	40.92	29.63	L	56.0	46.0	PASS
5	0.299	51.29	47.52	32.83	N	60	50	PASS
6	0.538	45.96	42.37	35.26	N	56.0	46.0	PASS
7	0.926	47.13	41.51	29.89	N	56.0	46.0	PASS
8	2.12	45.71	39.58	28.04	N	56.0	46.0	PASS

B. Test Plot:



(Plot A: L Phase)



(Plot B: N Phase)



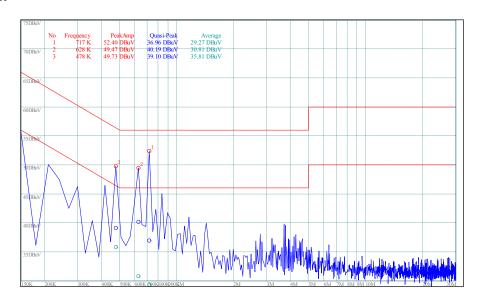
4.1.3.2 USB Test Mode

A. Test Verdict Recorded for Suspicious Points:

Nia	@Frequency	Measi	Measured Emission Level (dBμV)				Limit (dBµV)		
No.	(MHz)	PK	QP	AV	Phase	QP	AV	Verdict	
1	0.628	49.47	40.19	30.18	L	56.0	46.0	PASS	
2	0.717	52.4	36.96	29.27	L	56.0	46.0	PASS	
3	0.628	43.02			N	56.0	46.0	PASS	
4	2.84	38.53			N	56.0	46.0	PASS	
5	4.69	39.43			N	56.0	46.0	PASS	

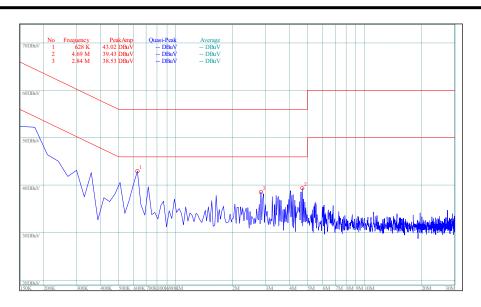
Note: "--" in the table above means that the emissions are too small to be measured and are at least 10 dB below the limit.

B. Test Plot:



(Plot A: L Phase)





(Plot B: N Phase)



4.2 Radiated Emission

4.2.1 Requirement

According to FCC section 15.109, the field strength of radiated emissions from unintentional radiators at a distance of 3 meters shall not exceed the following values:

Engagement non as (MIIa)	Field Strength			
Frequency range (MHz)	$\mu V/m$	dBμV/m		
30 - 88	100	40		
88 - 216	150	43.5		
216 - 960	200	46		
Above 960	500	54		

NOTE:

- a) Field Strength ($dB\mu V/m$) = 20*log[Field Strength ($\mu V/m$)].
- b) In the emission tables above, the tighter limit applies at the band edges.

4.2.2 Test Description

See section of this report.

4.2.3 Test Result

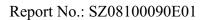
The maximum radiated emission is searched using PK, QP and AV detectors; the emission levels more than the limits, and that have narrow margins from the limits will be re-measured with AV and QP detectors. Both the vertical and the horizontal polarizations of the Test Antenna are considered to perform the tests. All test modes are considered, refer to recorded points and plots below.

4.2.3.1 GSM Test Mode

A. Test Verdict Recorded for Suspicious Points:

No.	@Frequency	Emission Level (dBμV/m)			Quasi-Peak	D agult
	(MHz)	PK	QP	Antenna Polarization	Limit (dBµV/m)	Result
1	54.25	34.21		Vertical	40	PASS
2	66.86	31.03		Vertical	40	PASS
3	246.31	38.93		Vertical	46	PASS
4	246.31	49.12	44.35	Horizontal	46	PASS
5	307.42	36.93		Horizontal	46	PASS

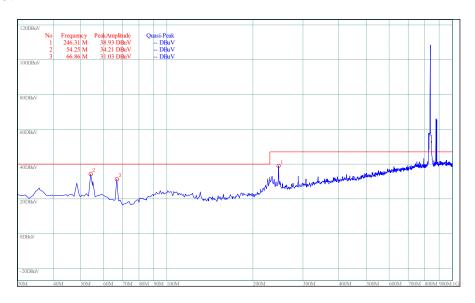
Note: "--" in the table above means that the emissions are too small to be measured and are at least 10



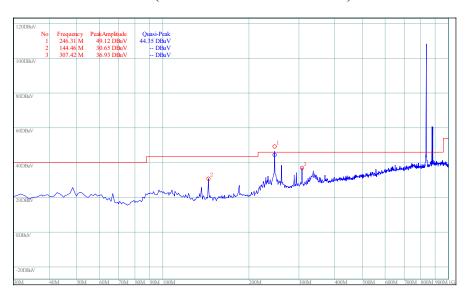


dB below the limit.

B. TestPlot



(Plot A: Test Antenna Vertical)



(Plot B: Test Antenna Horizontal)

4.2.3.2 USB Test Mode

A. Test Verdict Recorded for Suspicious Points:

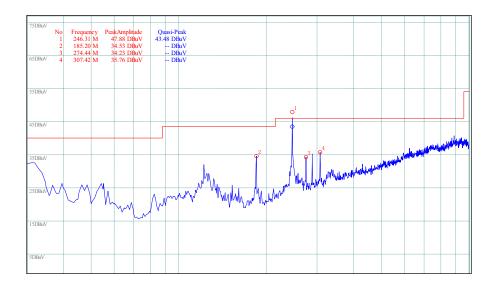
No.	@Frequency	Emission Level (dBμV/m)			Quasi-Peak	Result
	(MHz)	PK	QP	Antenna Polarization	Limit (dBµV/m)	Kesuit
1	185.20	34.53		Vertical	43.5	PASS
2	246.31	47.88	43.48	Vertical	46	PASS



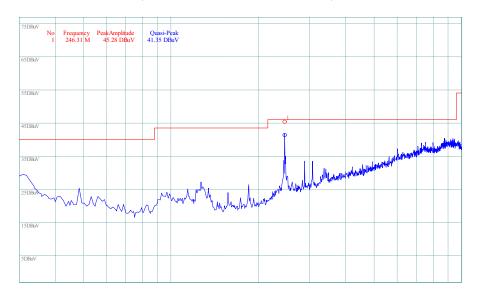
No.	@Frequency	Emission Level (dBμV/m)			Quasi-Peak	Result
	(MHz)	PK	QP	Antenna Polarization	Limit (dBµV/m)	Kesuit
3	274.44	34.23		Vertical	46	PASS
4	246.31	45.28	41.35	Horizontal	46	PASS

Note: "--" in the table above means that the emissions are too small to be measured and are at least 10 dB below the limit.

B. Test Plot:



(Plot A: Test Antenna Vertical)



(Plot B: Test Antenna Horizontal)

** END OF REPORT **